



# Official Grand Opening WB116 on Thursday, May 12

**8:30-8:40am**

**Registration**

**Please pre-register online by May 6 at**

<http://www.chem-eng.utoronto.ca/occam-grand-opening/>

**8:40-8:50am**

**Welcome: OCE and relationship to OCCAM – Rana Sodhi (ChemE/OCCAM) and Brad Brinton (OCE)**

**8:50am-12:15pm**

**Key methods at OCCAM – led by Charles Mims (ChemE/OCCAM)**

8:50am About OCCAM – Charles Mims (ChemE/OCCAM); Doug Perovic (MSE/OCCAM)

9:00am Applications of XPS – Tim Nunney (Thermo)

9:30am New developments in ToFSIMS – (Ion-ToF)

10:00am Coffee

10:15am LEIS: relationship to other techniques – Hidde Brongersma (Calipso/Eindhoven University of Technology/Imperial College London)

10:45am Auger electron spectroscopy – (Ulvac Phi)

11:15am AFM-based infrared spectroscopy—nanoscale chemical analysis with monolayer sensitivity – Eoghan Dillon (Anasys)

11:45am Joining the dots. How to design and build a successful core EM facility for materials analysis in collaboration with vendors – Ian Cotton (Hitachi)

**12:15-12:50pm Lunch (outside of WB116)**

**12:50-3:30pm Keynote Speakers – led by Doug Perovic (MSE/OCCAM)**

12:50pm Bill Theilacker (Medtronics)  
Characterization of surfaces and interfaces in the medical device industry

1:30pm John Watts (Surrey University, UK)  
Surface analysis in the service of materials science: metals, wood and paint

2:10pm Nigel Browning (PNNL, USA)  
Imaging materials dynamics in the TEM

2:50pm Peter Arrowsmith (BOTE Engineering)  
Contamination issues in electronics: selected case histories

**3:30-3:50pm Welcome – Grant Allen (ChemE) / Jun Nogami (MSE)**

**Funding Organizations – CFI and ORF**

**3:50-4:00pm Opening for the new facility – Dean or representative (FASE)**

**4:00-6:00pm Breakout sessions, networking, reception (Wallberg - first floor)**

- ToF-SIMS/LEIS - IonToF (Wallberg 107)
- XPS - Thermo (Wallberg 107/111)
- Auger - Ulvac Phi (Wallberg 111)
- AFM/IR - Anasys (Wallberg 104)
- Surface Profilometry - KLA-Tencor (Wallberg 104)
- Cryomicrotoming - Leica (Wallberg 104)
- Electron Microscopy - Hitachi (Wallberg 165)
  
- Thermo USA - Wallberg corridor
- SFR - Wallberg corridor
- CFI - Wallberg corridor
- ORF - Wallberg corridor
- OCE - Wallberg corridor